PCN Number:		201705	100	00A	0A PCN Date: June 23, 2017						
Title:		Qualificati select Dev	ion of Amkor and TI Clark as an additional Assembly and Test Sites and for vices					and Test Sites and for			
Customer			PCN Man	ador		Donti		Quality Car		~~	
Cont			<u>r ch mai</u>	agei	-	Dept:		Quality Ser	VIC	es	
	ige T										
		mbly Site							Assembly Materials		
	Desi				Electrical Specification				Mechanical Specification		
	Test		-					eiing			Test Process
		er Bump Sil er Fab Site	.e	\square	Wafer Bump Material		\exists		Wafer Bump Process Wafer Fab Process		
	vvale	er rad Sile		\square	Wafer Fab Materials			Water Tab Flocess			
						PCN D		S			
Desc	riptio	on of Char	ae:				Ctur				
				scrip	otion of cl	hange to	o provi	de correctio	n o	n f	the material differences
											ologize for any
incor	ivenie	nce this ma	ay have o	caus	ed.						
Terr	- T '			L			: f :'			- ا	
			•			•					TI Clark as and additional ces are as follows:
Asse		and rest si		e ue	vices liste	a below	. Con		rere	2110	ces are as follows:
		What			PS	Si	-	I Clark			Amkor
		Mold Com	pound		SID#20			1208625		SI	D#101384766
			ead finish		Matte			NiPdAu		-	Matte Sn
Bond W		Bond Wire	e, Diame	, Diameter		mils	Au, 1	.0 mils		<mark>Cu, 0.96 Mils</mark> Au, 0.96 Mils	
the (Upon expiry of this PCN TI will combine lead free solutions in a single <u>standard part number</u> , for the <u>CSD58888Q5D</u> – can ship with both Matte Sn and NiPdAu/Ag. Example: - Customer order for 7500units of CSD58888Q5D with 2500 units SPQ (Standard Pack Quantity per Reel).										
	 TI can satisfy the above order in one of the following ways. I. 3 Reels of NiPdAu finish. II. 3 Reels of Matte Sn finish 										
				2 Reels of Matte Sn and 1 reel of NiPdAu finish.							
			IV. 2	Ree	els of NiPo	dAu and	1 reel	of Matte Sn	n fir	nisł	h.
Test MQ.	Test coverage, insertions, conditions will remain consistent with current testing and verified with test										
Reason for Change:											
	Continuity of Supply										
	Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):										
None					,	, E					
Anti	cipate	ed impact	on Mate	eria	l Declara	tion					
Anticipated impact on MatNo Impact to the Material Declaration				Ma pr Up	aterial De oduction	claratior data and ction rel	d will b	be available	foll	ow	eports are driven from ving the production release. is can be obtained from the

Changes to product identification resulting from this PCN:					
Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (21L)	Assembly City		
PSI	PAC	PHL	Taguig City		
TI Clark	QAB	PHL	Angeles City		
Amkor	AP3	PHL	Binan		
BL: 5A (L)TO	arking (if included): for PAC= E for QAB = I	(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483SI2 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CC0:USA (22L) AS0: MLA (23L) AC0: MYS			
oduct Affected					
	st: Current AT site = PS	i & Clark, Additional AT site	= Amkor		

Group 2 Device list:	Current AT site= PSi,	Additional AT site =	<u>Amkor</u>				
CSD17575Q3	CSD18532NQ5B	CSD19502Q5B	SN1607042Q5B				
CSD17575Q3T	CSD18532NQ5BT	CSD19502Q5BT					
Group 3 Device list: Current AT site= PSi, Additional AT site = TI Clark							

CSD58888Q5D



Qualification Report

Phase 7 Power Block Qual in Amkor P3: CSD87333Q3D, CSD87334Q3D, CSD87335Q3D Approve Date 06-February-2017

Product Attributes

Attributes	Qual Device: CSD87333Q3D	Qual Device: CSD87334Q3D	Qual Device: CSD87335Q3D	
Assembly Site	AMKOR P3 A/T PHIL	AMKOR P3 A/T PHIL	AMKOR P3 A/T PHIL	
Package Family	DQZ	DQZ	DQZ	
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	
Wafer Fab Supplier	CFAB	CFAB	CFAB	
Wafer Fab Process	NEXFET-LV 30N10	NEXFET-LV 30N10	NEXFET-LV 30N10	

- QBS: Qual By Similarity

- Qual Device CSD87333Q3D is qualified at LEVEL1-260C

- Qual Device CSD87335Q3D is qualified at LEVEL1-260C

- Qual Device CSD87334Q3D is qualified at LEVEL 1-260C

- Device CSD87333Q3D contains multiple dies.

- Device CSD87334Q3D contains multiple dies.

- Device CSD87335Q3D contains multiple dies.

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: CSD87333Q3D	Qual Device: CSD87334Q3D	Qual Device: CSD87335Q3D
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	3/1/0 - Pass	3/1/0 - Pass	3/1/0 - Pass
PC	Preconditioning	(per the appropriate pkg level)	-	3/462/0	3/462/0
TC	**T/C -40C/125C	-40C/+125C (500,1000 Cycles)	-	3/231/0	3/231/0
TC	**T/C -55C/125C	-55C/+125C (500,1000 Cycles)	-	3/231/0	3/231/0

** Preconditioning was performed for Temperature Cycle as applicable

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green



5x6 QFN Q5D Power Block Qualification Summary NCH MOSFET – Gen 2.0 30-10

C SD87353Q5D Qualification Test Summary							
Stress	Conditions	Test Duration	Sample Size	Results			
HTRB	150°C/80% Rated Vds	1K hrs	3 lots x 77 units	Pass			
HTGB	150°C/80% Rated Vgs	1K hrs	3 lots x 77 units	Pass			
THB	85°C/85%R.H./80% Rated Vds	1K hrs	3 lots x 77 units	Pass			
Autoclave	121C/100% RH	96 hrs	3 lots x 77 units	Pass			
Intermittent Op Life	Delta Tj = 100°C 2 min on/2 min off	10K cycles	3 lots x 77 units	Pass			
Temp Cycle	-40°C to 125°C	1K cycles	3 lots x 77 units	Pass			

Pass = 0/77 x 3 lots

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MSL1 preconditioning performed on devices prior to THB, Autoclave, & Temp Cycle stresses

- External Visual @ 40X
- Temp Cycle: -40°C to +60°C, 5 cycles, 10 min dwell
- Bake: 24 hours @ 125°C
- Damp Heat: 168 hours @ 85°C/85% RH (Level 1)
- 3X reflow + flux + rinse, 260°C Pb free reflow temp

Original full qualification on CSD87353Q5D was run at PSi (above table). Clark assembly site is qualified by similarity since full qualification of 3 lots on CSD87350Q5D and full qualification of 1 lot on CSD87353Q5D was performed at Clark.

C SD87353Q5D Qualification Test Summary								
Stress	Conditions	Test Duration	Sample Size	Results				
HTRB	150°C/80% Rated Vds	1K hrs	1 lot x 77 units	Pass				
HTGB	150°C/80% Rated Vgs	1K hrs	1 lot x 77 units	Pass				
THB	85°C/85%R.H./80% Rated Vds	1K hrs	1 lot x 77 units	Pass				
Autoclave	121C/100% RH	96 hrs	1 lot x 77 units	Pass				
Intermittent Op Life	Delta Tj = 100°C 2 min on/2 min off	10K cycles	1 lot x 77 units	Pass				
Temp Cycle	-40°C to 125°C	1K cycles	1 lot x 77 units	Pass				

TI Information – Selective Disclosure

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com